

PINGHU CITY XIAO MING XING CHILDREN'S PRODUCTS CO.,LTD TEST REPORT

SCOPE OF WORK:

EMC directive (2014/30/EU) – EMC report

Model: XMX606

REPORT NUMBER 180702101SHA-001

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Report no. 180702101SHA-001

Applicant	PINGHU CITY XIAO MING XING CHILDREN'S PRODUCTS CO.,LTD EAST OF PINGLANG ROAD, ZHONGHUA VILLAGE,XINCANG TOWN, PINGHU CITY, ZHEJIANG, CHINA
Manufacturer	PINGHU CITY XIAO MING XING CHILDREN'S PRODUCTS CO.,LTD EAST OF PINGLANG ROAD, ZHONGHUA VILLAGE,XINCANG TOWN, PINGHU CITY, ZHEJIANG, CHINA
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Summary

The equipment complies with the requirements according to the following standard(s) or Specification:

EN 55014-1:2017: Electromagnetic compatibility - Requirements for household appliances, electric tools and similar apparatus Part 1: Emission

EN 55014-1: 2006+A1: 2009/+A2:2011: Electromagnetic compatibility - Requirements for household appliances, electric tools and similar apparatus Part 1: Emission

EN 55014-2:2015: Electromagnetic compatibility - Requirements for household appliances, electric tools and similar apparatus Part 2: Immunity - Product family standard

EN 61000-3-2:2014: Electromagnetic compatibility (EMC) - Part 3-2: Limits - Limits for harmonic current emissions (equipment input current \leq 16A per phase)

EN 61000-3-3:2013: Electromagnetic compatibility (EMC) - Part 3-3: Limits - Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current ≤ 16A per phase and not subject to conditional connection

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Contents

REVISIO	DN HISTORY	5
MEASU	REMENT RESULT SUMMARY	6
1. G	ENERAL INFORMATION	7
1.1	DESCRIPTION OF EQUIPMENT UNDER TEST (EUT)	7
1.2	DESCRIPTION OF TEST FACILITY	
2. TI	EST SPECIFICATIONS	
2.1	Normative Standards	
2.2	Mode of operation during the test	
2.3	TEST PERIPHERALS USED	10
2.4	RECORD OF CLIMATIC CONDITIONS	10
2.5	INSTRUMENT LIST	
2.6	MEASUREMENT UNCERTAINTY	14
EMISSIC	ON TEST	15
3. M	IAINS/LOAD/CONTROL TERMINAL CONTINUOUS DISTURBANCE VOLTAGE	15
3.1	TERMINAL VOLTAGE LIMITS FOR THE FREQUENCY RANGE 9kHz to 30MHz	15
	1.1 General limits	
	.1.2 Limits for mains port of tools	
3.2	BLOCK DIAGRAM OF TEST SETUP	
3.3 3.4	Test Setup and Test Procedure	
4. M	IAINS TERMINAL DISCONTINUOUS DISTURBANCE VOLTAGE/CLICK	
4.1	BLOCK DIAGRAM OF TEST SETUP	
4.2	TEST SETUP AND TEST PROCEDURE	
4.3	TEST PROTOCOL	22
5. C	ONTINUOUS DISTURBANCE POWER	23
5.1	CONTINUOUS DISTURBANCE POWER LIMIT	23
5.2	BLOCK DIAGRAM OF TEST SET UP	
5.3	Test Procedure	
5.4	TEST PROTOCOL	24
6. R	ADIATED EMISSION	26
6.1	Liмit	26
6.2	BLOCK DIAGRAM AND TEST SET UP	
6.3	TEST PROTOCOL	27
7. H	ARMONICS	29
7.1	BLOCK DIAGRAM OF TEST SETUP	29
7.2	Test Setup and Test Procedure	
7.3	TEST PROTOCOL	
8. V	OLTAGE FLUCTUATIONS-FLICKER	31
8.1	BLOCK DIAGRAM OF TEST SETUP	31
8.2	Test Setup and Test Procedure	31
-	2.1 Definition	
-	.2.2 Test condition	-
8.3	TEST PROTOCOL	32
IMMUN	NITY TEST	33

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	TROSTATIC DISCHARGE (ESD)	. 54
9.1 S	everity Level and Performance Criterion	34
9.1.1	Test level	34
9.1.2	Performance Criterion	34
9.2 B	lock Diagram of Test Setup	35
9.3 T	est Setup and Test Procedure	36
9.4 T	EST PROTOCOL	37
10. ELEC	TROMAGNETIC FIELD SUSCEPTIBILITY	. 38
10.1	Severity Level and Performance Criterion	38
10.1		
10.1		
10.1	BLOCK DIAGRAM OF TEST SETUP	
10.2	Test Setup and Test Procedure	
10.5	TEST PROTOCOL	
-	TRIC FAST TRANSIENT/BURST IMMUNITY TEST	
11.1	SEVERITY LEVEL AND PERFORMANCE CRITERION	
11.1		-
11.1	,	
11.2	BLOCK DIAGRAM OF TEST SETUP	
11.2	5 5 1 7 1	
11.2	5 5 1 7 1 5 7	
11.3	Test Setup and Test Procedure	
11.4	TEST PROTOCOL	43
12 5110		
12. JUK	GE IMMUNITY TEST	. 44
12. SOK		
	Severity Level and Performance Criterion	44
12.1	Severity Level and Performance Criterion	44 44
12.1 <i>12.1</i>	Severity Level and Performance Criterion .1 Test level .2 Performance Criterion	44 44 44
12.1 12.1 12.1	Severity Level and Performance Criterion	44 44 44 45
12.1 <i>12.1</i> <i>12.1</i> 12.2	SEVERITY LEVEL AND PERFORMANCE CRITERION	44 <i>44</i> <i>44</i> 45 45
12.1 <i>12.1</i> 12.2 12.3 12.4	SEVERITY LEVEL AND PERFORMANCE CRITERION 1 Test level	44 44 45 45 45
12.1 12.1 12.2 12.3 12.4 13. IMM	SEVERITY LEVEL AND PERFORMANCE CRITERION	44 44 45 45 45 45
12.1 12.1 12.2 12.3 12.4 13. IMM 13.1	SEVERITY LEVEL AND PERFORMANCE CRITERION	44 44 45 45 45 45 46
12.1 12.1 12.2 12.3 12.4 13. IMM 13.1 13.1	SEVERITY LEVEL AND PERFORMANCE CRITERION	44 44 45 45 45 45 46 46
12.1 12.1 12.2 12.3 12.4 13. IMM 13.1 13.1 13.1	SEVERITY LEVEL AND PERFORMANCE CRITERION 1 Test level 2 Performance Criterion BLOCK DIAGRAM OF TEST SETUP TEST SETUP AND TEST PROCEDURE TEST PROTOCOL IUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS SEVERITY LEVEL AND PERFORMANCE CRITERION 1 Test level 2 Performance Criterion	44 44 45 45 45 45 46 46
12.1 12.1 12.2 12.3 12.4 13. IMM 13.1 13.1 13.1 13.2	SEVERITY LEVEL AND PERFORMANCE CRITERION	44 44 45 45 45 45 46 46
12.1 12.1 12.2 12.3 12.4 13. IMM 13.1 13.1 13.2 13.3	SEVERITY LEVEL AND PERFORMANCE CRITERION	44 44 45 45 45 45 46 46
12.1 12.1 12.2 12.3 12.4 13. IMM 13.1 13.1 13.2 13.3 13.4	SEVERITY LEVEL AND PERFORMANCE CRITERION	44 44 45 45 45 45 45 46 46 46 46 47 48
12.1 12.1 12.2 12.3 12.4 13. IMM 13.1 13.1 13.2 13.3 13.4	SEVERITY LEVEL AND PERFORMANCE CRITERION	44 44 45 45 45 45 45 46 46 46 46 47 48
12.1 12.1 12.2 12.3 12.4 13. IMM 13.1 13.1 13.2 13.3 13.4	SEVERITY LEVEL AND PERFORMANCE CRITERION	44 44 45 45 46 46 46 46 46 48 48 49
12.1 12.1 12.2 12.3 12.4 13. IMM 13.1 13.1 13.2 13.3 13.4 14. VOL	Severity Level and Performance Criterion .1 Test level .2 Performance Criterion BLOCK DIAGRAM OF TEST SETUP TEST SETUP AND TEST PROCEDURE TEST PROTOCOL IUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS SEVERITY LEVEL AND PERFORMANCE CRITERION .1 Test level .2 Performance Criterion .1 Test PROCEDURE TEST SETUP AND TEST PROCEDURE TEST PROTOCOL TAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST SEVERITY LEVEL AND PERFORMANCE CRITERION .1 Test level	44 44 45 45 46 46 46 46 46 46 48 48 49 49
12.1 12.1 12.2 12.3 12.4 13. IMM 13.1 13.1 13.2 13.3 13.4 14. VOL 14.1	Severity Level and Performance Criterion .1 Test level .2 Performance Criterion BLOCK DIAGRAM OF TEST SETUP TEST SETUP AND TEST PROCEDURE TEST PROTOCOL IUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS SEVERITY LEVEL AND PERFORMANCE CRITERION .1 Test level .2 Performance Criterion .3 Performance Criterion .4 Test PROCEDURE TEST SETUP AND TEST PROCEDURE Test PROTOCOL TAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST SEVERITY LEVEL AND PERFORMANCE CRITERION .1 Test level	44 44 45 45 46 46 46 46 46 46 48 48 49 49
12.1 12.1 12.2 12.3 12.4 13. IMN 13.1 13.1 13.2 13.3 13.4 14. VOL 14.1 14.1	Severity Level and Performance Criterion .1 Test level .2 Performance Criterion BLOCK DIAGRAM OF TEST SETUP TEST SETUP AND TEST PROCEDURE TEST PROTOCOL IUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS SEVERITY LEVEL AND PERFORMANCE CRITERION .1 Test level .2 Performance Criterion .1 Test level .2 Performance Criterion .1 Test SETUP .2 Performance Criterion .1 Test SETUP .2 Performance Criterion .3 BLOCK DIAGRAM OF TEST SETUP TEST SETUP AND TEST PROCEDURE Test SETUP AND TEST PROCEDURE TEST PROTOCOL Test PROTOCOL IMAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST .2 Performance Criterion .1 Test level .2 Performance Criterion .1 Test level .2 Performance Criterion .3 Test level .4 Test level .5 Performance Criterion <t< td=""><td>44 44 45 45 45 45 46 46 46 46 46 47 48 49 49 49 49 49 49</td></t<>	44 44 45 45 45 45 46 46 46 46 46 47 48 49 49 49 49 49 49
12.1 12.1 12.2 12.3 12.4 13. IMN 13.1 13.1 13.2 13.3 13.4 14. VOL 14.1 14.1 14.1	Severity Level and Performance Criterion 1 Test level 2 Performance Criterion BLOCK DIAGRAM OF TEST SETUP TEST SETUP AND TEST PROCEDURE TEST PROTOCOL HUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS SEVERITY LEVEL AND PERFORMANCE CRITERION .1 Test level .2 Performance Criterion .1 Test level .2 Performance Criterion BLOCK DIAGRAM OF TEST SETUP	44 44 45 45 45 45 46 46 46 46 46 47 48 49 49 49 49 49 49 49
12.1 12.1 12.2 12.3 12.4 13. IMM 13.1 13.1 13.2 13.3 13.4 14. VOL 14.1 14.1 14.2	Severity Level and Performance Criterion .1 Test level .2 Performance Criterion BLOCK DIAGRAM OF TEST SETUP TEST SETUP AND TEST PROCEDURE TEST PROTOCOL IUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELDS SEVERITY LEVEL AND PERFORMANCE CRITERION .1 Test level .2 Performance Criterion .1 Test level .2 Performance Criterion .1 Test SETUP .2 Performance Criterion .1 Test SETUP .2 Performance Criterion .3 BLOCK DIAGRAM OF TEST SETUP TEST SETUP AND TEST PROCEDURE Test SETUP AND TEST PROCEDURE TEST PROTOCOL Test PROTOCOL IMAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST .2 Performance Criterion .1 Test level .2 Performance Criterion .1 Test level .2 Performance Criterion .3 Test level .4 Test level .5 Performance Criterion <t< td=""><td>44 44 45 45 45 46 46 46 46 46 46 46 47 48 49 49 49 49 50 50</td></t<>	44 44 45 45 45 46 46 46 46 46 46 46 47 48 49 49 49 49 50 50



Revision History

Report No.	Version	Description	Issued Date
180702101SHA-001	Rev. 01	Initial issue of report	August 15, 2018



Measurement result summary

TEST ITEM	TEST RESULT	NOTE
Mains terminal continuous disturbance voltage	Pass	
Mains terminal discontinuous disturbance voltage/click	NA	
Continuous disturbance power	Pass	
Radiated Emission	Pass	
Harmonics	Pass	
Voltage fluctuation-Flicker	Pass	
Electrostatic Discharge (ESD)	Pass	
RF electromagnetic field susceptibility	Pass	
Electric Fast Transient /Burst (EFT/B)	Pass	
Surge	Pass	
Injected Current	Pass	
Voltage dips and interruption	Pass	

Notes: 1: NA =Not Applicable

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1. GENERAL INFORMATION

1.1 Description of Equipment Under Test (EUT)

Product name	:	CHILDREN'S CAR
Type/Model	:	XMX606
Description of EUT	:	We tested the model XMX606 with the battery chargers: LK-D120100 and listed the worst data.
Rating	:	Battery: 12VDC Battery charger: Input: 230-240VAC~, 50Hz, 23W Output: 12VDC, 1A
EUT type	:	Table-top
EUT is toy, defined as		 Category A Category B Category C Category D Category E
Sample received date	:	July 20, 2018
Sample Identification No.	:	0180720-86
Date of test	:	August 10, 2018



1.2 Description of Test Facility

Address:Building 86, No. 1198 Qinzhou Road(North), Shanghai 200233, P.R. ChinaTelephone:86 21 61278200Telefax:86 21 54262353The test facility is:CNAS Accreditation Labrecognized, certified, or accredited by these organizations:CNAS Accreditation LabFCC Accredited Lab Designation Number: CN1175FCC Accredited Lab Designation Number: CN1175IC Registration Lab Registration Code No.: 2042B-1VCCI Registration Lab Registration No.: R-4243, G-845, C-4723, T-2252NVLAP Accreditation Lab NVLAP LAB CODE: 200849-0 A2LA Accreditation Lab	Name	:	Intertek Testing Services Shanghai
Telefax:86 21 54262353The test facility is recognized, certified, or accredited by these organizations:CNAS Accreditation Lab Registration No. CNAS L0139FCC Accredited Lab Designation Number: CN1175FCC Accredited Lab Designation Number: CN1175IC Registration Lab Registration code No.: 2042B-1VCCI Registration Lab Registration No.: R-4243, G-845, C-4723, T-2252NVLAP Accreditation Lab NVLAP LAB CODE: 200849-0	Address		Building 86, No. 1198 Qinzhou Road(North), Shanghai 200233, P.R. China
The test facility is recognized, certified, or accredited by these organizations:CNAS Accreditation Lab Registration No. CNAS L0139FCC Accredited Lab Designation Number: CN1175::IC Registration Lab Registration code No.: 2042B-1:VCCI Registration Lab Registration No.: R-4243, G-845, C-4723, T-2252NVLAP Accreditation Lab NVLAP LAB CODE: 200849-0	Telephone	:	86 21 61278200
recognized, certified, or accredited by these organizations FCC Accredited Lab Designation Number: CN1175 IC Registration Lab Registration code No.: 2042B-1 VCCI Registration Lab Registration No.: R-4243, G-845, C-4723, T-2252 NVLAP Accreditation Lab NVLAP LAB CODE: 200849-0	Telefax	:	86 21 54262353
Certificate Number: 3309.02	recognized, certified, or accredited by these	:	Registration No. CNAS L0139FCC Accredited LabDesignation Number: CN1175IC Registration LabRegistration code No.: 2042B-1VCCI Registration LabRegistration No.: R-4243, G-845, C-4723, T-2252NVLAP Accreditation LabNVLAP LAB CODE: 200849-0A2LA Accreditation Lab



2. TEST SPECIFICATIONS

2.1 Normative Standards

IEC 61000-4-2:2008: Electromagnetic Compatibility (EMC) – Part 4-2: testing and measurement techniques – electrostatic discharge immunity test

IEC 61000-4-3:2006+A1:2007+A1:2010: Electromagnetic Compatibility (EMC) – Part 4-3: testing and measurement techniques – radiated, radio frequency, electromagnetic field immunity test

IEC 61000-4-4:2012: Electromagnetic Compatibility (EMC) – Part 4-4: testing and measurement techniques – electric fast transient/burst immunity test

IEC 61000-4-5:2014: Electromagnetic Compatibility (EMC) – Part 4-5: testing and measurement techniques – section 5: surge immunity test

IEC 61000-4-6:2013: Electromagnetic Compatibility (EMC) – Part 4-6: testing and measurement techniques – section 6: immunity to conducted disturbance, induced by radio frequency field

IEC 61000-4-11:2004: Electromagnetic Compatibility (EMC) – Part 4-11: testing and measurement techniques –voltage dips, short interruption and voltage variations immunity test

IEC 61000-4-22:2010, Electromagnetic compatibility (EMC) – Part 4-22: Testing and measurement techniques – Radiated emissions and immunity measurements in fully anechoic rooms (FARs)

Note: there are no magnetic sensitive components included in this EUT and magnetic field immunity test according to EN 61000-4-8 is therefore not required.

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2.2 Mode of operation during the test

Within this test report, EUT was tested under all available operation modes and tested under its rating voltage and frequency. Other voltage and frequency is specified if used.

2.3 Test Peripherals used

Item No	Description	Band and Model	S/No
1	-	-	-

2.4 Record of climatic conditions

Test Item	Temperature (°C)	Relative Humidity (%)	Pressure (Kpa)
Mains terminal continuous disturbance voltage	24	48	101
Mains terminal discontinuous disturbance voltage/click	NA	NA	NA
Continuous disturbance power	24	48	101
Radiated Emission	27	52	101
Harmonics	NA	NA	NA
Voltage fluctuation-Flicker	NA	NA	NA
Electrostatic Discharge (ESD)	26	55	101
RF electromagnetic field susceptibility	27	52	101
Electric Fast Transient /Burst (EFT/B)	26	55	101
Surge	26	55	101
Injected Current	22	49	101
Voltage dips and interruption	26	55	101

Notes: NA =Not Applicable

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2.5 Instrument list

<mark>Condu</mark>	Conducted Emission / Disturbance Power / Tri-loop Test / CDN method					
Used	Equipment	Manufacturer	Туре	Internal no.	Due date	
\boxtimes	Test Receiver	R&S	ESCS 30	EC 2107	2018-09-12	
\boxtimes	A.M.N.	R&S	ESH2-Z5	EC 3119	2018-12-07	
	A.M.N.	R&S	ENV 216	EC 3393	2018-07-30	
	A.M.N.	R&S	ENV4200	EC 3558	2018-06-20	
\boxtimes	Absorbing clamp	R&S	MDS 21	EC 2108	2019-05-13	
	CDN	Schaffner	CDN M216	EC 2113-2	2019-03-15	
	CDN	Schaffner	CDN M316	EC 2113-1	2018-07-30	
	Attenuator	Weinschel	68-6-44	EC 3043-9	2019-02-05	
	Tri-loop	Schwarzbeck	HXYZ 9170	EC 3384	2018-10-11	
	Voltage Probe	Schwarzbeck	TK9420	EC 4888	2018-09-11	
	Current probe	R&S	EZ-17	EC 3221	2019-03-15	
	I.S.N.	FCC	FCC-TLISN -T2-02	EC 3754	2019-02-05	
	I.S.N.	FCC	FCC-TLISN -T4-02	EC 3755	2019-02-05	
	I.S.N.	FCC	FCC-TLISN -T8-02	EC 3756	2019-02-05	
\boxtimes	Shielded room	Zhongyu	-	EC 2838	2019-01-07	
Discontinuous Disturbance Voltage						
Used	Equipment	Manufacturer	Туре	Internal no.	Due date	
	Click meter	AFJ	DDA55	EC 5320	2018-01-17	
	A.M.N.	AFJ	LS16C	EC 5220-1	2018-12-07	
	Shielded room	Zhongyu	-	EC 2838	2019-01-07	
Radiated Emission						
Used		Manufacturer	Туре	Internal no.	Due date	
\boxtimes	Test Receiver	R&S	ESIB 26	EC 3045	2018-09-12	
\boxtimes	Bilog Antenna	TESEQ	CBL 6112D	EC 4206	2019-05-31	
	Horn antenna	R&S	HF 906	EC 3049	2018-11-17	
	Horn antenna	ETS	3117	EC 4792-1	2019-01-09	
	Horn antenna	ΤΟΥΟ	HAP18-26W	EC 4792-3	2020-07-09	
	Pre-amplifier	R&S	Pre-amp 18	EC5262	2018-06-20	
	Active loop antenna	Schwarzbeck	FMZB1519	EC 5345	2019-03-07	
\boxtimes	Semi-anechoic chamber	Albatross project	-	EC 3048	2018-09-15	

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Harmo	Harmonics / Flicker / Low-frequency immunity test							
Used	Equipment	Manufacturer	Туре	Internal no.	Due date			
	Harmonic-flicker	CI	5001ix-PACS-1	EC 2110	2018-11-08			
	Three phase	EM TEST	PFS 503N	EC 5383	2019-01-31			
	Harmonic-flicker system	EM TEST	DPA 503N	EC 5383-1	2017-12-29			
ESD								
Used	Equipment	Manufacturer	Туре	Internal no.	Due date			
	ESD generator	EM TEST	ditto	EC 2956	2018-05-12			
\boxtimes	ESD generator	TESEQ	NSG 437	EC 4792-4	2019-03-22			
\boxtimes	Shielded room	Zhongyu	-	EC 2839	2019-01-14			
<mark>EFT / S</mark>	urge / Voltage Dips							
Used	Equipment	Manufacturer	Туре	Internal no.	Due date			
\boxtimes	Conduct immunity system	EM TEST	UCS 500M6B	EC 2958	2019-04-07			
\boxtimes	Automatic transformer	EM TEST	MV2616	EC 2957	2019-04-07			
	Capacity clamp	EM TEST	HFK	EC 2959	2019-02-13			
	Surge generator	EM TEST	TSS 500M2F	EC 2960	2018-08-09			
	Surge generator	EM TEST	TSS 500M4	EC 2961	2019-01-05			
	Surge Coupling network	EM TEST	CNV 504M	EC 2958-2	2019-02-05			
	Surge Coupling network	EM TEST	CNV 504S1	EC 2958-1	2019-02-05			
	DIPs generator	SANKI	SKS-1130GT	EC 5033	2019-01-05			
	Ring wave generator	SANKI	SKS-1206GB	EC 5033-1	2019-01-05			
	EFT generator	SANKI	SKS-0404IB	EC 5033-2	2019-03-08			
	Surge generator	SANKI	SKS-0506GB-30	EC 5033-3	2019-03-08			
\boxtimes	Shielded room	Zhongyu	-	EC 2839	2019-01-14			
<mark>Condu</mark>	Conducted Immunity							
Used	Equipment	Manufacturer	Туре	Internal no.	Due date			
\boxtimes	Signal generator	R&S	SML 01	EC 2338	2018-09-10			
\boxtimes	Power amplifier	AR	75A250	EC 3043-1	2019-07-13			
\boxtimes	Attenuator	EM TEST	ATT6/75	EC 3043-3	2019-02-05			
\boxtimes	CDN	Frankonia	CDN M2M316	EC 5969	2019-03-15			
	CDN	Schaffner	CDN M316	EC 2113-1	2018-07-30			
	CDN	EM TEST	CDN T2	EC 4970	2018-09-06			
	CDN	EM TEST	CDN T4	EC 3043-4	2019-02-05			
	CDN	EM TEST	CDN M1/16A	EC 4792-6	2018-10-08			
	CDN	EM TEST	CDN M1/16A	EC 4792-7	2018-09-06			

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□CDNEM TESTCDN M1/32AEC4792-102019-02-05□CDNEM TESTCDNM3N/16AEC 4792-122019-02-05□CDNEM TESTCDNM3N/32AEC 4792-132019-02-05□CDNEM TESTCDN T8-RI45EC 4792-152018-09-06□EM clampEM TESTEM 101EC 3043-62018-12-07□DDCARDC 2600EC 3043-52019-02-05RadiatutimentyWanfacturerTypeInternal no.Due date☑Signal generatorR&SSMR 20EC 3044-12019-01-29☑Power amplifierAR250W1000BEC 5818-22019-04-19☑Power amplifierBONNBLMA1060-100EC 5818-42019-04-19☑Log-period antennaARAT 1080EC 3044-72018-08-15□Horn antennaARAT 4002EC 3044-72018-08-15□Horn antennaARFL17000EC 5818-12018-06-19□Field meterARFL17000EC 5818-32019-04-19☑Power sensorKeysightN1914AEC 5818-32019-03-05□Power sensorKeysightN1914AEC 5338-12019-03-05□Power sensorAgilentN5181AEC 5338-22019-03-05□Power sensorAgilentN5181AEC 51762019-03-05□MXG Analog Signal GeneratorAgilentN5181AEC 51762019-03-05 <t< th=""><th></th><th></th><th></th><th></th><th></th><th></th></t<>																																																																																																																																																																																																																			
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Due date Used Equipment 7/1-24 S.M.LE EC 2323</td><th></th><td></td><td>Litepoint</td><td>lqxel</td><td>EC 5176</td><td>2019-01-09</td></tr> <tr><td>Used Equipment Manufacturer Type Internal no. Due date</td><th></th><td>Test Receiver</td><td>R&S</td><td>ESCI 7</td><td>EC 4501</td><td>2018-09-12</td></tr> <tr><td>Therom- $7/1-2\Delta$ SM F FC 2323</td><td colspan="8">Additional instrument</td></tr> <tr><td>Therom- 7/1-2A SMIE FC 2323</td><th>Used</th><td>Equipment</td><td>Manufacturer</td><td>Туре</td><td>Internal no.</td><td>Due date</td></tr> <tr><td>K Lot 2019-06-15 Hygrograph 2019-06-15</td><th>\boxtimes</th><td>Therom- Hygrograph</td><td>ZJ1-2A</td><td>S.M.I.F.</td><td>EC 2323</td><td>2019-06-15</td></tr> <tr><td>Image: Solution of the second stateImage: Solution of the second stateZJ1-2AS.M.I.F.EC 33242019-04-15Image: Solution of the second stateHygrographZJ1-2AS.M.I.F.EC 3324</td><th>\boxtimes</th><td>Therom-</td><td>ZJ1-2A</td><td>S.M.I.F.</td><td>EC 3324</td><td>2019-04-15</td></tr> <tr><td>Therom-ZJ1-2A S.M.I.F.</td><th></th><td>Therom- Hygrograph</td><td>ZJ1-2A</td><td>S.M.I.F.</td><td>EC 3325</td><td>2019-03-28</td></tr> <tr><td>I ⊠ I FC 3325 I 2019-03-28</td><th>\boxtimes</th><td>Therom- Hygrograph</td><td>ZJ1-2A</td><td>S.M.I.F.</td><td>EC 3326</td><td>2019-03-28</td></tr> <tr><td>Hygrograph EC 3325 2019-03-28 Therom- ZJ1-2A S.M.I.F. EC 3326 2019-03-28</td><th>\boxtimes</th><td>Pressure meter</td><td>YM3</td><td>Shanghai Mengde</td><td>EC 3320</td><td>2019-06-29</td></tr>		CDN	EM TEST	CDNM3N/32A	EC 4792-13	2019-02-05	□DDCARDC 2600EC 3043-52019-02-05Radiated ImmunityUsedEquipmentManufacturerTypeInternal no.Due date☑Signal generatorR&SSMR 20EC 3044-12019-01-29☑Power amplifierAR250W1000BEC 5818-22019-04-19☑Power amplifierBONNBLMA1060-100EC 5818-42019-04-19☑Power amplifierBONNBLMA1060-100EC 3044-72018-08-15□Horn antennaARAT 1080EC 3044-82018-08-15□Horn antennaSchwarzbeckSTLP 9149EC58812018-06-19□Field meterARFL17000EC 5818-12018-05-11□Power sensorKeysightN1914AEC 5818-32019-04-19☑Fully-anechoic chamberAlbatross project-EC 30472018-09-15RF testUVector Signal GeneratorAgilentN5182BEC 51752019-03-05□Power sensorAgilentN5181AEC 5338-12019-03-05□Mobile Test SystemLitepointIqxelEC 51762019-03-05□Test ReceiverR&SESCI 7EC 45012018-09-12Additional instrumentUIqxelEC 51762019-01-09□Test ReceiverR&SESCI 7EC 45012018-09-12Additional instrumentUIqxelEC 51762019-01-09		CDN	EM TEST	CDN T8-RJ45	EC 4792-15	2018-09-06	Balaiated ImmunityHanufacturerTypeInternal no.Due dateUSedEquipmentManufacturerTypeInternal no.Due date☑Signal generatorR&SSMR 20EC 3044-12019-01-29☑Power amplifierAR250W1000BEC 5818-22019-04-19☑Power amplifierBONNBLMA1060-100EC 5818-42019-04-19☑Log-period antennaARAT 1080EC 3044-72018-08-15□Horn antennaARAT 4002EC 3044-82018-08-24□Horn antennaARAT 4002EC 3044-82018-06-19□Field meterARFL17000EC 5818-12018-06-19□Field meterARFL17000EC 5818-32019-04-19☑Fully-anechoic chamberAlbatross project-EC 30472018-09-15RF testUsedEquipmentManufacturerTypeInternal no.Due date□PXA Signal GeneratorKeysightN9030AEC 53382019-03-05□Power sensorAgilentU2021XAEC 5338-12019-03-05□Power Signal GeneratorAgilentN5182BEC 51752019-03-05□MXG Analog Signal GeneratorAgilentN5181AEC 5338-22019-03-05□Mobile Test SystemLitepointIqxelEC 51762019-01-09□Test ReceiverR&SESCI 7EC 45012018-09-12 <t< td=""><th></th><td>EM clamp</td><td>EM TEST</td><td>EM 101</td><td>EC 3043-6</td><td>2018-12-07</td></t<>		EM clamp	EM TEST	EM 101	EC 3043-6	2018-12-07	UsedEquipmentManufacturerTypeInternal no.Due date⊠Signal generatorR&SSMR 20EC 3044-12019-01-29⊠Power amplifierAR250W1000BEC 5818-22019-04-19⊠Power amplifierBONNBLMA1060-100EC 5818-42019-04-19⊠Log-period antennaARAT 1080EC 3044-72018-08-15□Horn antennaARAT 4002EC 3044-82018-08-15□Horn antennaARAT 4002EC 3044-82018-06-19□Field meterARFL17000EC 5818-12018-06-19□Field meterARFL17000EC 5818-12018-05-11□Power sensorKeysightN1914AEC 5818-32019-04-19⊠Fully-anechoic chamberAlbatross project-EC 30472018-09-15RF testUsedEquipmentManufacturerTypeInternal no.Due date□Power sensorAgilentU2021XAEC 5338-12019-03-05□Power sensorAgilentN5181AEC 5338-22019-03-05□MXG Analog Signal GeneratorAgilentN5181AEC 5338-22019-03-05□Mobile Test SystemLitepointIqxelEC 51762019-01-09□Test ReceiverR&SESCI 7EC 45012018-09-12Additional instrumentUsedEquipmentManufacturerTypeInternal no.Use		DDC	AR	DC 2600	EC 3043-5	2019-02-05	UsedEquipmentManufacturerTypeInternal no.Due date⊠Signal generatorR&SSMR 20EC 3044-12019-01-29⊠Power amplifierAR250W1000BEC 5818-22019-04-19⊠Power amplifierBONNBLMA1060-100EC 5818-42019-04-19⊠Log-period antennaARAT 1080EC 3044-72018-08-15□Horn antennaARAT 4002EC 3044-82018-08-15□Horn antennaARAT 4002EC 3044-82018-06-19□Field meterARFL17000EC 5818-12018-06-19□Field meterARFL17000EC 5818-12018-05-11□Power sensorKeysightN1914AEC 5818-32019-04-19⊠Fully-anechoic chamberAlbatross project-EC 30472018-09-15RF testUsedEquipmentManufacturerTypeInternal no.Due date□Power sensorAgilentU2021XAEC 5338-12019-03-05□Power sensorAgilentN5181AEC 5338-22019-03-05□MXG Analog Signal GeneratorAgilentN5181AEC 5338-22019-03-05□Mobile Test SystemLitepointIqxelEC 51762019-01-09□Test ReceiverR&SESCI 7EC 45012018-09-12Additional instrumentUsedEquipmentManufacturerTypeInternal no.Use	Radiat	ed Immunity		1			Signal generatorR&SSMR 20EC 3044-12019-01-29Power amplifierAR250W1000BEC 5818-22019-04-19Power amplifierBONNBLMA1060-100EC 5818-42019-04-19Image: State of the state			Manufacturer	Туре	Internal no.	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2.6 Measurement Uncertainty

Measurement	Frequency	Expanded Uncertainty (k=2) (±)
Conducted emission at mains north	9kHz ~ 150kHz	3.52 dB
Conducted emission at mains ports	150kHz ~ 30MHz	3.19 dB
Continuous disturbance voltage at telecom ports	150kHz ~ 30MHz	3.64 dB
Continuous disturbance current at telecom ports	150kHz ~ 30MHz	2.62 dB
Mains terminal discontinuous disturbance voltage/click	-	3.76 dB
Continuous disturbance power	30MHz ~ 300MHz	4.35 dB
Radiated Emissions up to 1 GHz	30MHz ~ 1GHz	4.90 dB
Radiated Emissions above 1 GHz	1GHz ~ 6GHz	5.02 dB
	6GHz ~ 18GHz	5.28 dB
Harmonic current emission	-	3.90%
Voltage fluctuations and flicker	-	10.34%
ESD	-	6.65%
Radiated susceptibility	-	2.38%
EFT test at main terminal	-	11.57%
EFT test at signal/telecom terminal	-	11.62%
Surge test at main terminal	-	11.57%
Injected current test at main terminal	-	1.88 dB
Injected current test at unshielded signal terminal	-	3.41 dB
Voltage dips and interruption	-	6.05%

Emission Test

3. Mains/Load/Control Terminal Continuous Disturbance Voltage

Test result: PASS

3.1 Terminal Voltage Limits for the frequency range 9kHz to 30MHz

3.1.1 General limits

	Mains ports		Associated ports			
Frequency range (MHz)	Disturbance voltage		Disturbance voltage		Disturbance current	
(14112)	Limits dB(μV)		Limits dB(µV)		Limits dB(µV)	
	Quasi-pea	k Average	Quasi-peak	Average	Quasi-peak	Average
0.15 ~ 0.5	66~56*	66~56*	80	70	40 ~ 30 *	30~20*
0.5 ~ 5.0	56	56	74	64	30	20
5.0 ~ 30	60	60	74	64	50	20
Notes:						

1. * means the limit decreasing linearly with the logarithm of the frequency in the range 0.15MHz to 0.5MHz.

2. If the quasi-peak measurements meet the average limit, the EUT shall be deemed to meet both limits and the measurements using the average detector need not be carried out.

3.1.2 Limits for mains port of tools

	P ≤ 700 W		700 W < P \leq 1 000 W		P > 1 (000 W
Frequency range	Limits	dB(μV)	Limits	dB(μV)	Limits	dB(μV)
(MHz)	Quasi-pea	k Average	Quasi-peak	Average	Quasi-peak	Average
0.15-0.35	66-59*	59-49*	70-63*	63-53*	76-69*	69 ~ 59 *
0.35-5	59	49	63	53	69	59
5-30	64	54	68	58	74	64

Notes:

1. * means the limit decreasing linearly with the logarithm of the frequency in the range 0.15MHz to 0.35MHz.

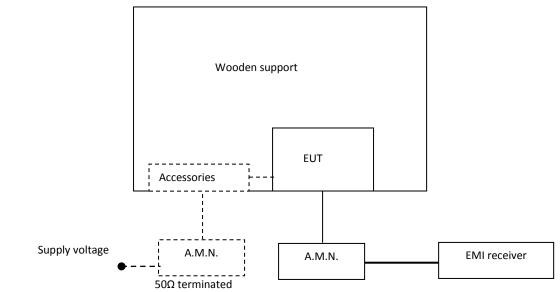
2. If the quasi-peak measurements meet the average limit, the EUT shall be deemed to meet both limits and the measurements using the average detector need not be carried out.



Total Quality. Assured.

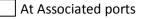
3.2 Block Diagram of Test Setup

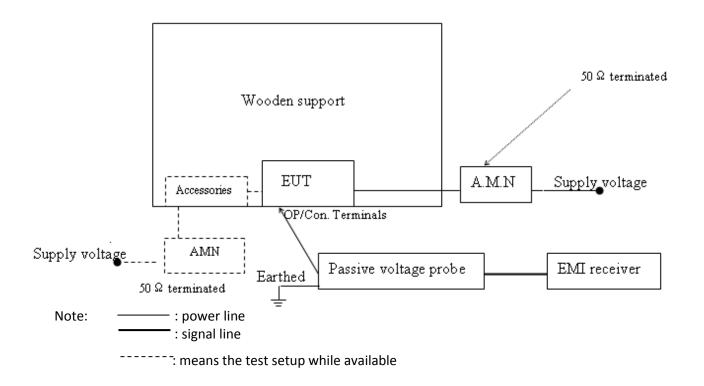
At mains terminal



For table top equipment, wooden support is 0.8m height table

For floor standing equipment, wooden support is 0.1m height rack.







Total Quality. Assured.

3.3 **Test Setup and Test Procedure**

Measurement was performed in shielded room, and instruments used were according to clause 5.1 of EN 55014-1 if applicable.

Detailed test procedure and arrangement was according to clause 5.2 of EN 55014-1.

Measurement methods was according to clause 5.4 of EN 55014-1.

Operation conditions of EUT was according to clause 6 of EN 55014-1.

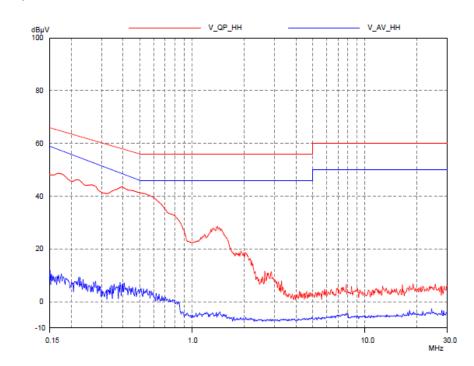
Frequency range 150kHz – 30MHz was checked and EMI receiver measurement bandwidth was set to 9kHz.



3.4 Test Protocol

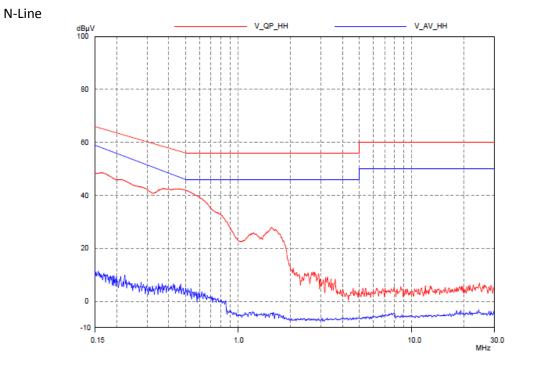
For Mains ports: Pass

L-Line



		Quasi-peak		Average		
Frequency (MHz)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)
0.16	*	65.30	*	*	58.10	*
0.24	*	62.40	*	*	54.40	*
0.50	*	56.00	*	*	46.00	*
1.40	*	56.00	*	*	46.00	*
2.00	*	56.00	*	*	46.00	*
3.50	*	56.00	*	*	46.00	*
6.00	*	60.00	*	*	50.00	*
10.00	*	60.00	*	*	50.00	*
Note: * means th	e emission le	evel 10dB bel	low the rele	vant limit.		





		Quasi-peak		Average					
Frequency (MHz)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)			
0.16	*	65.30	*	*	58.10	*			
0.24	*	62.40	*	*	54.40	*			
0.50	*	56.00	*	*	46.00	*			
1.40	*	56.00	*	*	46.00	*			
2.00	*	56.00	*	*	46.00	*			
3.50	*	56.00	*	*	46.00	*			
6.00	*	60.00	*	*	50.00	*			
10.00	*	60.00	*	*	50.00	*			
Note: * means th	Note: * means the emission level 20dB below the relevant limit.								

Remark: 1. Correct Factor = LISN Factor + Cable Loss, the value was added to Original Receiver Reading by the software automatically.

- 2. Corrected Reading = Original Receiver Reading + Correct Factor
- 3. Margin = Limit Corrected Reading
- 4. If the PK Corrected Reading is lower than AV limit, the AV test can be elided.

Example: Assuming LISN Factor = 10.00dB, Cable Loss = 2.00dB,

Original Receiver Reading = 10.00dBuV, Limit = 66.00dBuV. Then Correct Factor = 10.00 + 2.00 = 12.00dB; Corrected Reading = 10dBuV + 12.00dB = 22.00dBuV; Margin = 66.00dBuV - 22.00dBuV = 44.00dB.



For Associated ports: NA

	Quasi-peak			Average		
Frequency (MHz)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)
Note: * means th	e emission le	vel 20dB bel	ow the relev	vant limit.		

- Remark: 1. Correct Factor = LISN Factor + Cable Loss, the value was added to Original Receiver Reading by the software automatically.
 - 2. Corrected Reading = Original Receiver Reading + Correct Factor
 - 3. Margin = Limit Corrected Reading
 - 4. If the PK Corrected Reading is lower than AV limit, the AV test can be elided.

Example: Assuming LISN Factor = 10.00dB, Cable Loss = 2.00dB,

Original Receiver Reading = 10.00dBuV, Limit = 66.00dBuV. Then Correct Factor = 10.00 + 2.00 = 12.00dB;

Corrected Reading = 10dBuV + 12.00dB = 22.00dBuV;

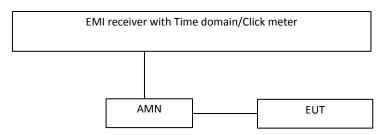
Margin = 66.00dBuV - 22.00dBuV = 44.00dB.

Total Quality. Assured.

Mains terminal discontinuous disturbance voltage/click 4.

Test result: NA

4.1 **Block Diagram of Test Setup**



4.2 **Test Setup and Test Procedure**

Measurement was performed in shielded room, and instruments used were according to clause 5.1 of EN 55014-1 if applicable.

Detailed test procedure and arrangement was according to clause 5.2 of EN 55014-1.

Measurement methods was according to clause 5.4 of EN 55014-1.

Operation conditions of EUT was according to clause 6 of EN 55014-1.

0.15MHz, 0.5MHz, 1.4MHz and 30MHz were spot checked, and upper quartile methods used during measurement.

The final judgment of test result was according to figure 6 of EN 55014-1.



4.3 Test Protocol

0.15	0.5	1.4	30.0				
66.0	56.0	56.0	60.0				
Test result Image: Construction of the second s							
	0.15 66.0						

Total Quality. Assured.

5. Continuous disturbance power

Test result:

5.1 Continuous disturbance power limit

Pass

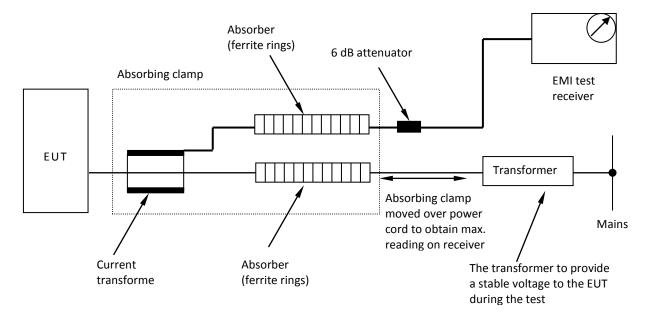
	Gene	eral	P ≤ 700 W		$P \le 700 \text{ W}$ 700 W < P $\le 1000 \text{ W}$		P > 1 0	00 W
Frequency range	Limits o	dB(μV)	Limits	dB(μV)	Limits d	lB(μV)	Limits d	lB(μV)
(MHz)	Quasi-peak	Average	Quasi-pea	k Average	Quasi-peak	Average	Quasi-peak	Average
30-300	45-55*	35-45*	45-55*	35-45*	49-59*	39-49*	55-65*	45 55*
Notoci								

Notes:

1. * means the limit decreasing linearly with the logarithm of the frequency in the range 30MHz to 300MHz.

2. If the quasi-peak measurements meet the average limit, the EUT shall be deemed to meet both limits and the measurements using the average detector need not be carried out.

5.2 Block diagram of test set up



5.3 Test Procedure

Measurement was performed in shielded room, and instruments used were according to clause 5.1 of EN 55014-1 if applicable.

Detailed test procedure and arrangement was according to clause 5.3 of EN 55014-1.

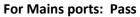
Measurement methods was according to clause 5.4 of EN 55014-1.

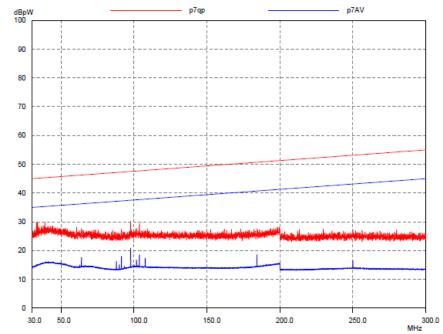
Operation conditions of EUT was according to clause 6 of EN 55014-1.

Frequency range 30MHz – 300MHz was checked and EMI receiver measurement bandwidth was set to 120kHz.



5.4 Test Protocol





		Quasi-peak		Average		
Frequency (MHz)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)
30.00	*	45.0	*	*	35.0	*
35.05	*	45.2	*	*	35.2	*
65.00	*	46.3	*	*	36.3	*
90.00	*	47.2	*	*	37.2	*
180.00	*	50.6	*	*	40.6	*
220.00	*	52.0	*	*	42.0	*
300.00	*	55.0	*	*	45.0	*
Note: * means th	e emission le	vel 20dB he	low the relev	vant limit		

Note: * means the emission level 20dB below the relevant limit.

Remark: 1. Correct Factor = Clamp Factor + Cable Loss, the value was added to Original Receiver Reading by the software automatically.

- 2. Corrected Reading = Original Receiver Reading + Correct Factor
- 3. Margin = Limit Corrected Reading
- 4. If the PK Corrected Reading is lower than AV limit, the AV test can be elided.

Example: Assuming Clamp Factor = 10.00dB, Cable Loss = 2.00dB,

Original Receiver Reading = 10.00dBuV, Limit = 66.00dBuV.

Then Correct Factor = 10.00 + 2.00 = 12.00dB;

Corrected Reading = 10dBuV + 12.00dB = 22.00dBuV;

Margin = 66.00dBuV - 22.00dBuV = 44.00dB.



For Associated ports: NA

		Quasi-peak			Average		
Frequency (MHz)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)	Corrected Reading (dBuV)	Limit (dBuV)	Margin (dB)	
Note: * means th	e emission le	evel 20dB be	low the rele	vant limit.			

Remark: 1. Correct Factor = LISN Factor + Cable Loss, the value was added to Original Receiver Reading by the software automatically.

- 2. Corrected Reading = Original Receiver Reading + Correct Factor
- 3. Margin = Limit Corrected Reading
- 4. If the PK Corrected Reading is lower than AV limit, the AV test can be elided.

Example: Assuming LISN Factor = 10.00dB, Cable Loss = 2.00dB,

Original Receiver Reading = 10.00dBuV, Limit = 66.00dBuV. Then Correct Factor = 10.00 + 2.00 = 12.00dB; Corrected Reading = 10dBuV + 12.00dB = 22.00dBuV; Margin = 66.00dBuV - 22.00dBuV = 44.00dB.



6. Radiated emission

Test result:

As for in the disturbance power test all emission readings from the EUT are lower than the applicable limits (Table 7) reduced by the margin (Table 8) and the maximum clock frequency is less than 30MHz, the EUT is deemed to comply with the Radiated Emission requirement without test.

6.1 Limit

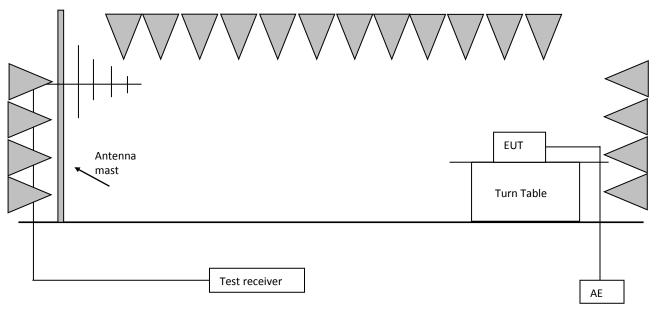
Radiated emission limit from frequency range 30MHz – 1000MHz

PASS

Frequency (MHz)	Permitted limit in dBµV/m (Quasi-peak) of Measurement Distance 3m	Permitted limit in dBµV/m (Quasi-peak) of Measurement Distance 10m
30 ~ 230	40	30
230 ~ 300	47	37
Notes: 1. For the measurem 20dB/10 decades.	ent distance other than 3m and 10m	a, the limit is varied according to

2. The gray rows are selected items.

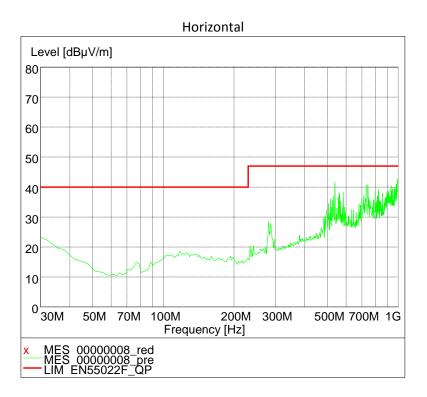
6.2 Block diagram and test set up

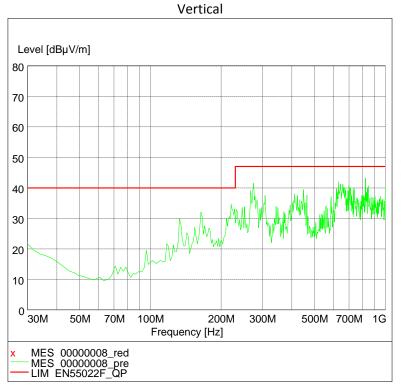


The measurement was applied in a semi-anechoic chamber. Operation conditions of EUT was according to clause 6 of EN 55014-1. Measurement was performed according to clause 10 of CISPR 32. Setting of EUT is according to clause 5.3.4.3 of EN 55014-1. The bandwidth setting on test receiver was 120kHz. The frequency range from 30MHz to 300MHz was checked.



6.3 Test Protocol





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Polarization	Frequency (MHz)	Corrected Reading (dBuV/m)	Limits (dBuV/m)	Margin (dBuV/m)
	92.2	*	40	*
	146.63	*	40	*
Llovinontol	226.33	*	40	*
Horizontal	494.58	*	47	*
	718.13	*	47	*
	918.35	*	47	*
	123.3	*	40	*
	158.29	*	40	*
Vertical	220.5	*	40	*
Vertical	230.0	*	47	*
	679.25	*	47	*
	735.63	*	47	*

Note: * means margin >10dB.

Remark: 1. Corrected Reading = Original Receiver Reading + Correct Factor

2. Margin = Limit - Corrected Reading

3. If the PK Corrected Reading is lower than AV limit, the AV test can be elided.

Example: Assuming Antenna Factor = 30.20dB/m, Cable Loss = 2.00dB,

Gain of Preamplifier = 32.00dB, Original Receiver Reading = 10.00dBuV, Limit = 40.00dBuV/m. Corrected Reading = 10dBuV + 0.20dB/m = 10.20dBuV/m;

Margin = 40.00dBuV/m - 10.20dBuV/m = 29.80dB.

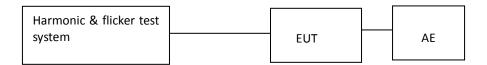


7. Harmonics

 \square

Test result: PASS

7.1 Block Diagram of Test Setup



7.2 Test Setup and Test Procedure

Harmonics of the fundamental current were measured up to 40 order harmonics using a digital power meter with an analogue output and frequency analyser which was integrated in the harmonic & flicker test system. The measurements were carried out under steady conditions.

Measuring instrumentation according to IEC 61000-4-7:2002+A1:2008

This product is not defined as lighting equipment, and has rated power less than 75W, therefore, no limit apply according to EN 61000-3-2

The EUT is kitchen machines as listed in the scope of IEC 60335-2-14, therefore, is deemed to conform to the harmonic current limits of this standard without further testing.



Test Protocol

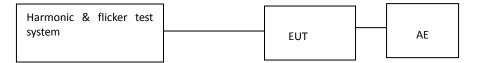
7.3

Report No. 180702101SHA-001

8. Voltage Fluctuations-Flicker

Test result: PASS

8.1 Block Diagram of Test Setup



8.2 Test Setup and Test Procedure

8.2.1 Definition

- Flicker: impression of unsteadiness of visual sensation induced by a light stimulus whose luminance or spectral distribution fluctuates with time.
- Pst: Short-term flicker severity.
- Plt: long-term flicker severity.
- dc: maximum steady state voltage change during an observation period.
- dmax: maximum absolute voltage change during an observation period.
- d(t): time function of the relative r.m.s. voltage change evaluated as a single value for each successive half period between zero-crossings of the source voltage, except during time interval in which the voltage is a steady-state condition for at least 1s.

8.2.2 Test condition

The EUT was set to produce the most unfavorable sequence of voltage changes.

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8.3 Test Protocol

The tested object operated under the operating condition specified in EN 61000-3-3 The following limits apply

- the value of Pst shall not be greater than 1,0.
- the value of Plt shall not be greater than 0,65.
- Tmax, the accumulated time value of d(t) with a deviation exceeding 3,3 % during a single voltage change at the EUT terminals, shall not exceed 500 ms.
- the maximum relative steady-state voltage change, dc, shall not exceed 3,3 %.
- the maximum relative voltage change dmax, shall not exceed:

4% without additional conditions.

6 % for equipment which is:

- switched manually, or
- switched automatically more frequently than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds), or manual restart, after a power supply interruption.
- 7 % for equipment which is:

- attended whilst in use (for example: hair dryers, vacuum cleaners, kitchen equipment such as mixers, garden equipment such as lawn mowers, portable tools such as electric drills), or

- switched on automatically, or is intended to be switched on manually, no more than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds) or manual restart, after a power supply interruption.

for manual switch, dmax is measured in accordance with Annex B of standard, average dmax is calculated from 24 times measurement.

According to EN 61000-3-3 clause 6.1 & A.2, the EUT is either unlikely to produce significant voltage fluctuations/flicker or no limit and test were required by technical analysis and sample evaluation on the product.



Immunity Test

Performance criteria

The performance criteria are based on the general criteria of the standard and derived from the product specification

Criterion A: Normal Performance within limits specified by the manufacturer, request or purchaser.

Criterion B: Continue to operate as intended after the test. No degradation of performance or loss of function. During the test degradation of performance is allowed, however no change of actual operating state or stored date.

Criterion C: Temporary loss of function is allowed, provided the function is self-recoverable or can be restored by the operation of the controls.

Categories of apparatus

Category I (fulfill the relevant immunity requirements without testing)

Category II (Shall fulfill the tests: ESD, EFT, Inject current, Surge, Dips)

Category III (Shall fulfill the tests: ESD, EM fields*)

Category IV (Shall fulfill the tests: ESD, EFT, Inject current, Surge, Dips, EM fields)

Note: *only applicable to the ride on toys operating with electronic devices.

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9. Electrostatic Discharge (ESD)

Test result: PASS

9.1 Severity Level and Performance Criterion

9.1.1 Test level

1a – Contact discharge		1b – Air discharge	
Level	Test voltage kV	Level	Test voltage kV
1	2	1	2
2	4	2	4
3	6	3	8
4	8	4	15
Х	Special	X	Special
Notos		1	

Notes:

1."X" is an open level. The level has to be specified in the dedicated equipment specification. If higher voltages than those shown are specified, special test equipment may be needed.

2. The gray rows were the selected test level.

9.1.2 Performance Criterion

Performance criterion: B

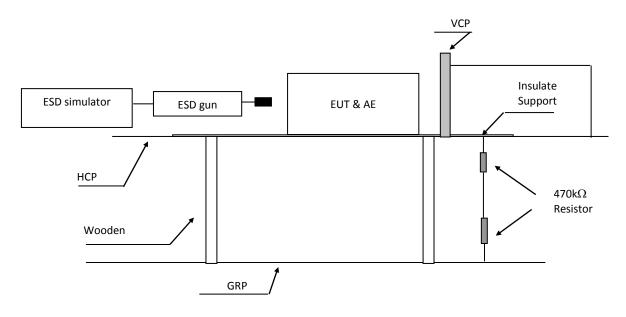
Report No. 180702101SHA-001

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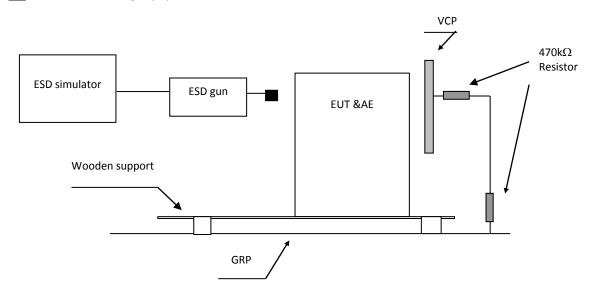
9.2 Block Diagram of Test Setup

For table-top equipment



Note: HCP means <u>H</u>orizontal <u>C</u>oupling <u>P</u>lane VCP means <u>V</u>ertical <u>C</u>oupling <u>P</u>lane GRP means <u>G</u>round <u>R</u>eference <u>P</u>lane Wooden support is a 0.8m height table

For floor standing equipment



Note: VCP means <u>V</u>ertical <u>C</u>oupling <u>P</u>lane GRP means <u>G</u>round <u>R</u>eference <u>P</u>lane Wooden support is a 0.1m height rack



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9.3 **Test Setup and Test Procedure**

Measurement was performed in shielded room.

Measurement and setting of EUT was applied according to IEC 61000-4-2 Clasuse 7. The test method and equipment was specified by IEC 61000-4-2 with the modifications by EN 55014-2 clause 5.1.

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9.4 Test Protocol

Test point #	Test level [kV]	Air/ Contact	Polarity (+/-)	Pass/Fail/NA	Comment
А	2/4	Contact	+/-	Pass	All touchable screws of enclosure
В	2/4	Contact	+/-	Pass	Accessible metal parts of the EUT
С	2/4/8	Air	+/-	Pass	Air gap of the switch, button
D	2/4/8	Air	+/-	Pass	The air in-taking opening
E	2/4/8	Air	+/-	Pass	Slots around the EUT

Direct discharges were applied at the following selected points:

Indirect contact discharges were applied to the VCP and the HCP at the following selected points:

For table top equipment

Point	Description	Point	Pass/Fail/NA
HCP f	0,1m from the front of the EUT	Edge of centre, corner on HCP	-
HCP b	0,1m from the back of the EUT	Edge of centre, corner on HCP	-
HCP r	0,1m from the right side of the EUT	Edge of centre, corner on HCP	-
HCP I	0,1m from the left side of the EUT	Edge of centre, corner on HCP	-
VCP f	0,1m from the front of the EUT	Edge of centre, corner on VCP	-
VCP b	0,1m from the back of the EUT	Edge of centre, corner on VCP	-
VCP r	0,1m from the right of the EUT	Edge of centre, corner on VCP	-
VCP I	0,1m from the left of the EUT	Edge of centre, corner on VCP	-

For floor standing equipment

Point	Description	Point	Pass/Fail/NA
VCP f	0,1m from the front of the EUT	Edge of centre, corner on VCP	Pass
VCP b	0,1m from the back of the EUT	Edge of centre, corner on VCP	Pass
VCP r	0,1m from the right of the EUT	Edge of centre, corner on VCP	Pass
VCP I	0,1m from the left of the EUT	Edge of centre, corner on VCP	Pass

Observation: All the functions were operated as normal during and after test. **Conclusion:** The EUT met the requirements of Performance Criterion B.

Total Quality. Assured.

Electromagnetic field susceptibility 10.

Test result:

10.1 Severity Level and Performance Criterion

Pass

10.1.1 Test level

Level	Test field strength V/m
1	1
2	3
3	10
Х	Special
Notes:	

Notes:

1. X is an open test level. This level may be given in the product specification.

2. The gray row is the selected test level.

10.1.2 Performance Criterion

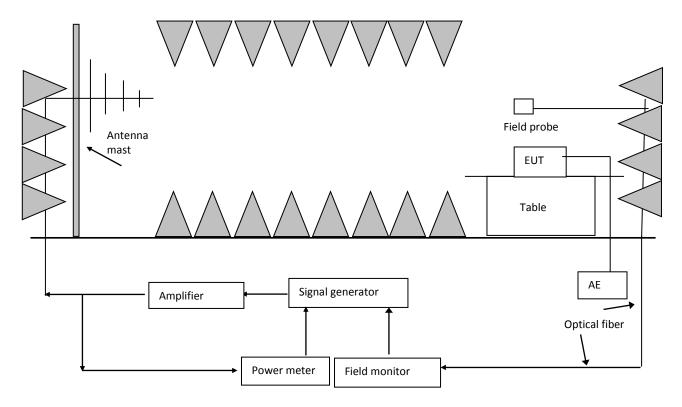
Performance criterion: A



Report No. 180702101SHA-001

Total Quality. Assured.

10.2 Block diagram of test setup



10.3 Test Setup and Test Procedure

Measurement was performed in full-anechoic chamber. Measurement and setting of EUT was applied according to IEC 61000-4-3 clause 7. The test method and equipment was specified by IEC 61000-4-3 with additions and modifications by EN 55014-2 clause 5.5.

10.4 Test Protocol

Test no.:	Frequency (MHz)	Polarization	Test level V/m	Modulation	Exposed location	Pass/Fail/NA	Commen t
1	80-1000	H & V	3	1kHz, 80%, SW, AM, 1% step size	All sides	Pass	-

Observation: All the functions were operated as normal during and after test. **Conclusion:** The EUT met the requirements of Performance Criterion A.

Total Quality. Assured.

Electric Fast Transient/Burst Immunity Test 11.

Test result: PASS

11.1 Severity Level and Performance Criterion

11.1.1 Test level

Open circuit output test voltage (±10%) and repetition rate of the impulses (±20%)						
Level	Input and output	a.c. power ports	Input and output d.c. power ports Signal lines and control lines ports			
	Voltage peak kV	Repetition rate kHz	Voltage peak kV	Repetition rate kHz		
1	0.5	5	0.25	5		
2	1	5	0.5	5		
3	2	5	1	5		
4	4	5	2	5		
Х	Special	Special	Special	Special		
Notes :						

1. "X" is an open level. The level has to be specified in the dedicated equipment specification.

2. The gray rows were the selected test level.

11.1.2 Performance Criterion

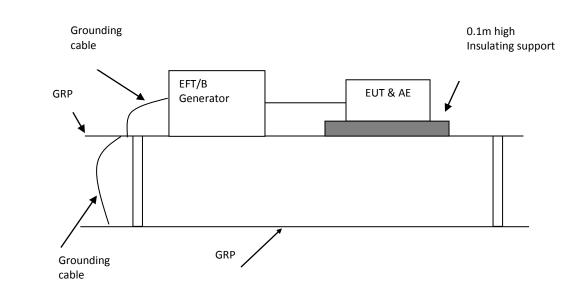
Performance criterion **B**

Total Quality. Assured.

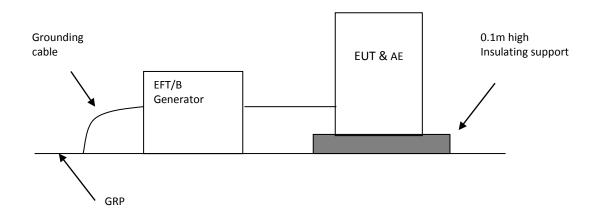
11.2 Block Diagram of Test Setup

11.2.1 Block Diagram for input a.c./d.c. power line

For table-top equipment



Sor floor standing equipment

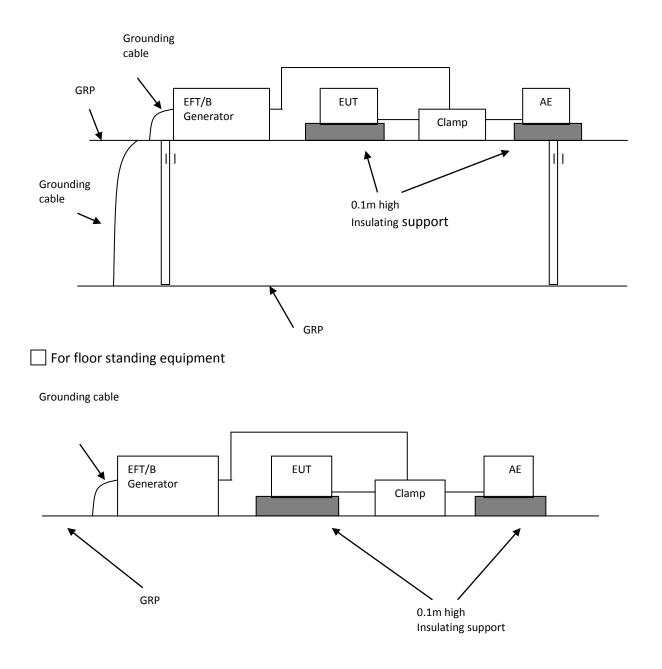




Total Quality. Assured.

11.2.2 Block Diagram for output a.c./d.c. power line or signal/control lines

For table-top equipment



11.3 **Test Setup and Test Procedure**

Measurement was performed in shielded room. Measurement and setting of EUT was applied according to IEC 61000-4-4 clause 7. The test method and equipment was specified by IEC 61000-4-4 with additions and modifications by EN 55014-2 clause 5.2.

Report No. 180702101SHA-001

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11.4 Test Protocol

Test No.	Level [kV]	Polarity +/-	Repetition rate kHz	Line for test	Pass/Fail/NA
1	1	+/-	5	a.c. power ports	Pass
2	0.5	+/-	5	d.c. power ports	NA
3	0.5	+/-	5	Signal lines and control lines	NA

Observation: All the functions were operated as normal during and after test. **Conclusion:** The EUT met the requirements of Performance Criterion B.

Total Quality. Assured.

12. Surge Immunity Test

Test result: PASS

12.1 Severity Level and Performance Criterion

12.1.1 Test level

Level	Open-circuit test voltage ±10% kV				
1	0.5				
2	1.0				
3	2.0				
4	4.0				
Χ*	Special				
Notes: 1."X" is an open class. This level can be specified in the product Specification					

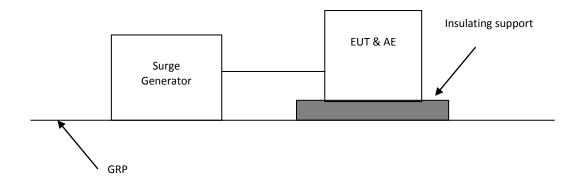
2. The gray rows are the selected level.

12.1.2 Performance Criterion

Performance criterion **B**

Total Quality. Assured.

12.2 Block Diagram of Test Setup



12.3 Test Setup and Test Procedure

Measurement was performed in shielded room. Measurement and setting of EUT was applied according to IEC 61000-4-5 clause 7. The test method and equipment was specified by IEC 61000-4-5 with modifications by EN 55014-2 clause 5.6.

12.4 Test Protocol

Test No.	Level [kV]	Polarity +/-	Angle	Line for test	Pass/Fail/NA
1	1	+	90 ⁰	a.c. Mains (line to earth)	NA
2	1	-	270 ⁰	a.c. Mains (line to earth)	NA
3	1	+	90 ⁰	a.c. Mains (line to line)	Pass
4	1	-	270 ⁰	a.c. Mains (line to line)	Pass
5	2	+	90 ⁰	a.c. Mains (line to earth)	NA
6	2	-	270 ⁰	a.c. Mains (line to earth)	NA

Observation: All the functions were operated as normal during and after test. **Conclusion:** The EUT met the requirements of Performance Criterion B.

Total Quality. Assured.

Immunity to Conducted Disturbances, Induced by Radio-frequency Fields 13.

Test result: PASS

Severity Level and Performance Criterion 13.1

13.1.1 Test level

Level	Voltage level (e.m.f.)			
	U ₀ [dB(uV)]	U ₀ (V)		
1	120	1		
2	130	3		
3	140	10		
Х	Special	Special		

1. "X" is an open level. 2. The gray row is the selected test level.

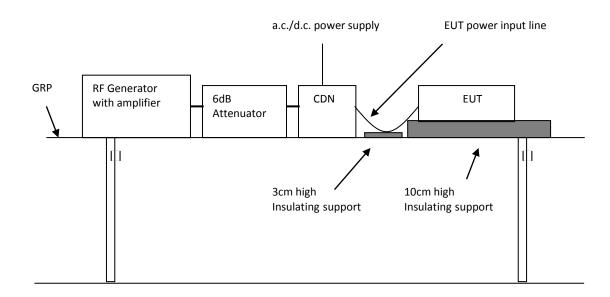
13.1.2 Performance Criterion

Performance criterion: A

Block Diagram of Test Setup 13.2

13.2.1 Block Diagram for a.c./d.c input power line

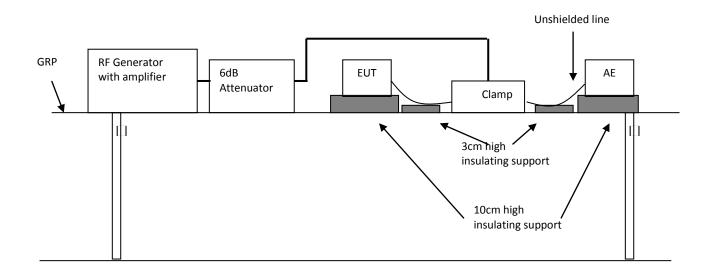
Block Diagram for a.c./d.c input power line



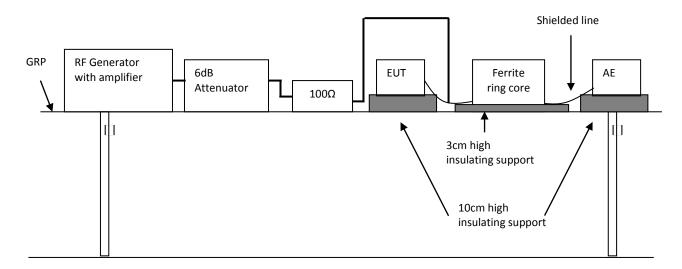


13.2.2 Block Diagram for output a.c./d.c. power line or signal/control lines

Unshielded line



Shielded line



13.3 Test Setup and Test Procedure

Measurement was performed in shielded room. Measurement and setting of EUT was applied according to IEC 61000-4-6 clause 7. The test method and equipment was specified by IEC 61000-4-6 with additions and modifications by EN 55014-2 clause 5.3, 5.4.

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13.4 Test Protocol

EUT is not required for electromagnetic susceptibility

Test	Frequency	Level	Modulation	Injected point	Pass/Fail/NA
No.	(MHz)	V (r.m.s.)			
1	0.15~230	3	1kHz, 80%, SW,	a.c. power ports	Pass
			AM,		
			1% step size		
2	0.15~230	1	1kHz, 80%, SW,	d.c. power ports	-
			AM,		
			1% step size		
3	0.15~230	1	1kHz, 80%, SW,	signal lines and	-
			AM,	control lines	
			1% step size		

For EUT test Electromagnetic field susceptibility

· .							
	Test	Frequency	Level	Modulation	Injected point	Pass/Fail/NA	
	No.	(MHz)	V (r.m.s.)				
	1	0.15~80	3	1kHz, 80%, SW,	a.c. power ports	NA	
				AM,			
				1% step size			
Ī	2	0.15~80	1	1kHz, 80%, SW,	d.c. power ports	-	
				AM,			
				1% step size			
Ī	3	0.15~80	1	1kHz, 80%, SW,	signal lines and	-	
				AM,	control lines		
				1% step size			

Observation: All the functions were operated as normal during and after test. **Conclusion:** The EUT met the requirements of Performance Criterion A.

14. Voltage Dips, Short Interruptions and Voltage Variations Immunity Test

Test result: PASS

14.1 Severity Level and Performance Criterion

14.1.1 Test level

Test level	Voltage dip and short interruptions	Duration (in period)	
% U _T	% U _τ	50Hz	60Hz
0	100	0.5 cycle	0.5 cycle
40	60	10 cycles	12 cycles
70	30	25 cycles	30 cycles

Notes:

1. "*" for 0.5 period, the test shall be made in positive and negative polarity, i.e. starting at 0° and 180°, respectively.

2. "**" means "x" is an open duration. This duration can be given in the product specification. Utilities in Europe have measured dips and short interruptions of duration between $\frac{1}{2}$ a period and 3000 periods, but duration less than 50 periods are most common.

3. If the EUT is tested for voltage dips of 100%, it is generally unnecessary to test for other levels for the same durations. However, for some cases (safeguard systems or electro-mechanical devices) it is not true. The product specification or product committee shall give an indication of the applicability of this note.

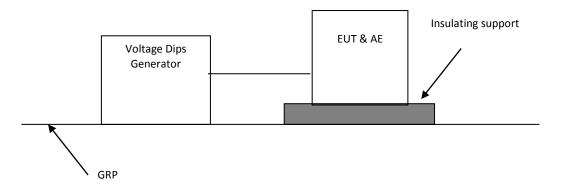
4. The gray rows are selected test level.

14.1.2 Performance Criterion

Performance criterion: C

Total Quality. Assured.

14.2 Block diagram of test setup



14.3 Test Setup and Test Procedure

Measurement was performed in shielded room. Measurement and setting of EUT was applied according to IEC 61000-4-11 clause 7. The test method and equipment was specified by IEC 61000-4-11 with additions and modifications by EN 55014-2 clause 5.7.

14.4 Test Protocol

Test no.	% U _T	Voltage dip and short interruptions % UT	Duration (in periods)	Pass/Fail/NA
1	70	30%	25 cycles at 50Hz	Pass
			30 cycles at 60Hz	NA
2	40	60%	10 cycles at 50Hz	Pass
			12 cycles at 60Hz	NA
3	0	100% pos half cycle	0.5 cycle at 50Hz	Pass
			0.5 cycle at 60Hz	NA
4	4 0 100% neg half cycle		0.5 cycle at 50Hz	Pass
			0.5 cycle at 60Hz	NA

Observation: At test level of 70%, the EUT worked unsteadily. Once the interference is removed, it recovered its normal mode at once

Conclusion: The EUT met the requirements of Performance Criterion B and C.



Appendix I: Photograph of equipment under test







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